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01/25/02

# U.S. UTILITY Patent Application

PATENT NUMBER and  
ISSUE DATE

APPL NUM 10058544	FILING DATE 01/25/2002	CLASS 324	SUBCLASS 754.000	GAU 2829	EXAMINER TANG, M
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**\*\*APPLICANTS:** Scott Mitchell; Reynaldo Rincon; Jerry Broz; Gerard Laugier;

**\*\*CONTINUING DATA VERIFIED:** *None ALT*

**\*\* FOREIGN APPLICATIONS VERIFIED:** *None ALT*

PG-PUB DO NOT PUBLISH ☐

RESCIND ☐

Foreign priority claimed

☐ yes ☒ no

35 USC 119 conditions met

☐ yes ☒ no

Verified and Acknowledged Examiners's initials

*ALT*

ATTORNEY DOCKET NO

TI-32531

**TITLE :** Multiple contact vertical probe solution enabling kelvin connection benefits for conductive bump probing

U.S. DEPT. OF COMM./PAT. & TM-PTO-436L (Rev. 12-94)

## NOTICE OF ALLOWANCE MAILED

<b>ISSUE FEE</b>	
Amount Due	Date Paid



**TERMINAL  
DISCLAIMER**

Assistant Examiner

Primary Examiner

**PREPARED FOR ISSUE**

## CLAIMS ALLOWED

Total Claims

Print Claim for  
O.G.

## DRAWING

Sheets Drwg.

Figs. Drwg.

Print Fig.

Application Examiner

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